

Notice of References Cited

Application/Control No.

10/725,401

Applicant(s)/Patent Under
Reexamination
YOSHIDA, AKIHIRO

Examiner

Chia-Wei A. Chen

Art Unit

2609

Page 1 of 1

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|------------------|----------------|
| * | A | US-5,838,371 | 11-1998 | Hirose et al. | 348/240.2 |
| * | B | US-5,883,666 | 03-1999 | Kyuma et al. | 348/229.1 |
| * | C | US-2005/0031330 A1 | 02-2005 | Nonaka et al. | 396/104 |
| * | D | US-7,034,878 | 04-2006 | Matsushima, Yuki | 348/333.03 |
| * | E | US-2003/0219168 A1 | 11-2003 | Kawakubo, Takuji | 382/260 |
| * | F | US-5,696,850 | 12-1997 | Parulski et al. | 382/261 |
| * | G | US-4,975,726 | 12-1990 | Kuga et al. | 396/101 |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|----------------|----------------|
| | N | JP 06014261 | 01-1994 | Japan | ARAI, HIDEYUKI | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.